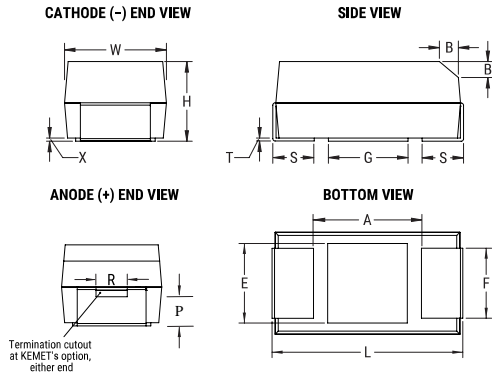


T494, Tantalum, MnO2 Tantalum, 22 uF, 10%, 20 VDC, SMD, MnO2, Molded, Low ESR, 300 mOhms, 7343, Height Max = 3.1mm



| General Information | |
|---------------------|----------------------------|
| Supplier: | KEMET |
| Series: | T494 |
| Dielectric: | MnO2 Tantalum |
| Style: | SMD Chip |
| Description: | SMD, MnO2, Molded, Low ESR |
| Features: | Low ESR |
| RoHS: | Yes |
| Termination: | Tin |
| Shelf Life: | 156 Weeks |
| MSL: | 1 |

| Dimensions | |
|------------|-----------------|
| Footprint | 7343 |
| L | 7.3mm +/-0.3mm |
| W | 4.3mm +/-0.3mm |
| H | 2.8mm +/-0.3mm |
| T | 0.13mm REF |
| S | 1.3mm +/-0.3mm |
| F | 2.4mm +/-0.1mm |
| A | 3.6mm MIN |
| B | 0.5mm +/-0.15mm |
| E | 3.5mm REF |
| G | 3.5mm REF |
| P | 0.9mm REF |
| R | 1mm REF |
| X | 0.1mm +/-0.1mm |

| Specifications | |
|------------------------|--|
| Capacitance: | 22 uF |
| Capacitance Tolerance: | 10% |
| Voltage DC: | 20 VDC (85C), 13.4 VDC (125C) |
| Temperature Range: | -55/+125C |
| Rated Temperature: | 85°C |
| Dissipation Factor: | 6.00% 120Hz 20C |
| Failure Rate: | N/A |
| Resistance: | 0.3 Ohms (100kHz) |
| Ripple Current: | 707 mAmps (100kHz 25C), 636.3 mAmps (85C), 282.8 mAmps (125C) |
| Leakage Current: | 4.4 uA (5min 20C) |

| Packaging Specifications | |
|--------------------------|------------|
| Weight: | 446.84 mg |
| Packaging: | T&R, 178mm |
| Packaging Quantity: | 500 |

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